Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/612,534	QIAN ET AL.
Examiner	Art Unit
John L. Goodrow	1756

SEARCHED			
Class	Subclass	Date	Examiner
430	114	8/8/2005	JG
	137.22		
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	115		
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INTERFERENCE SEARCHED			
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inventor name search	8/8/2005	JG
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